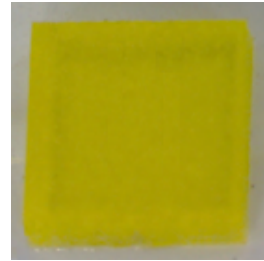


Direct TV Application

WICOP

SWWVA2S0E (WICOP 1140 2Cell MJT)



Product Brief

Description

- This SMT LED comes in standard PKG dimension.
- This has a phosphor layer on surface of Blue Chip without Lead Frame & Gold-wire.
- Because of the good thermal character, The WICOP 2Cell MJT (YR) allow to perform with high reliability.

Features and Benefits

- White colored SMT package
- Low Thermal Resistance
- Own patent reserved
- RoHS Complaint
- Pb-free Reflow Soldering application
- Suitable for all SMT assembly and soldering methods (Must not be hand soldering)

Key Applications

- Flat Backlighting (LCD, Display)
- MNT, TV etc.

Table of Contents

Index	
• Product Brief	
• Table of Contents	
• Performance Characteristics	
• Characteristic Diagram	
• Reliability Test	
• Color Bin Structure	
• Mechanical Dimension	
• Material Structure	
• Product Nomenclature	
• Reflow Soldering Characteristics	
• Handling of Silicone Resin for LEDs	
• Precaution For Use	
• Company Information	

Performance Characteristics **T.B.D**

Table 1. Absolute Maximum Ratings ($T_a = 25^{\circ}\text{C}$)

Parameter	Symbol	Value	Unit
Power Dissipation	P_d^{*1}	2000	mW
DC Forward Current	I_F	300	mA
Peak Forward Current	I_{FM}^{*2}	TBD	mA
Operating Temperature	T_{opr}	-30 ~ +85	$^{\circ}\text{C}$
Storage Temperature	T_{stg}	-40 ~ +100	$^{\circ}\text{C}$
Junction Temperature	$T_j \text{ max}$	125	$^{\circ}\text{C}$

Notes :

- (1) Care is to be taken that power dissipation does not exceed the absolute maximum rating of the product.
- (2) 1/10 Duty Cycle @ 100Hz .

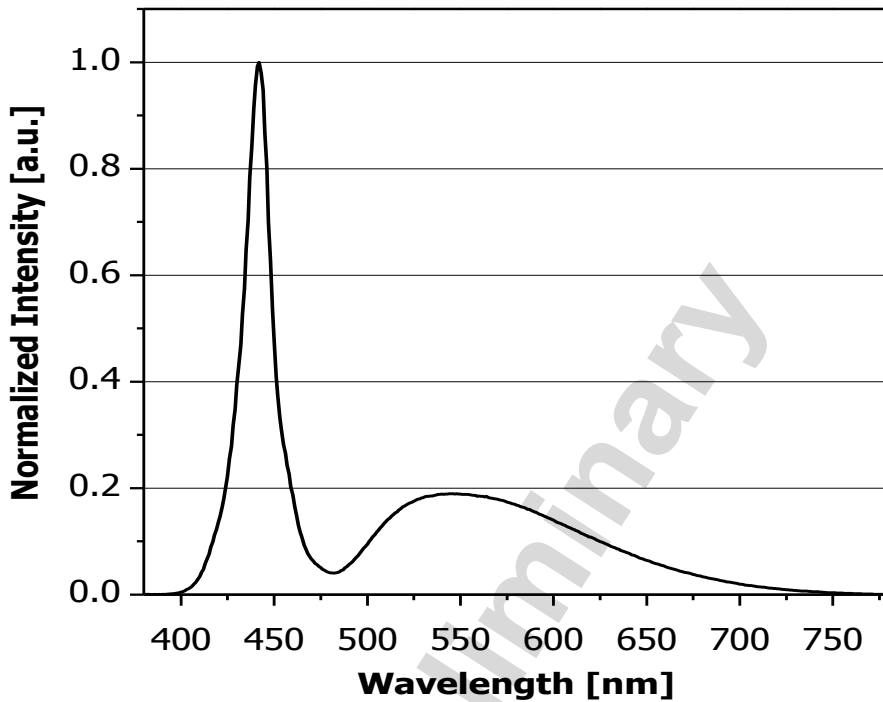
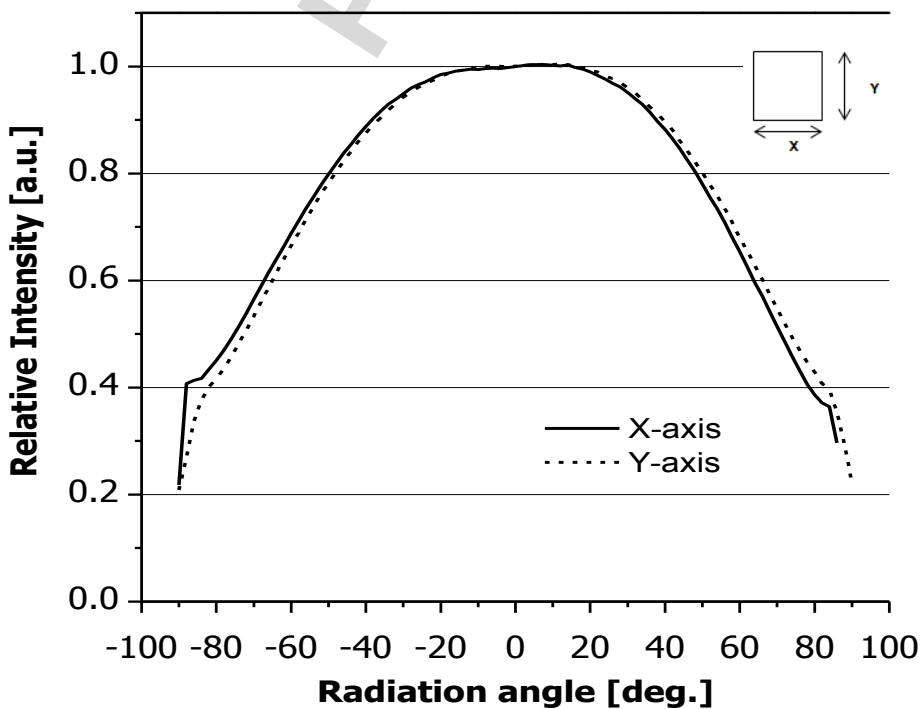
Table 2. Electro Optical Characteristics ($T_a = 25^{\circ}\text{C}$)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Forward Voltage ^{*1}	V_F	$I_F = 175\text{mA}$	5.80	6.20	6.60	V
Luminous Flux ^{*2}	Φ_V	$I_F = 175\text{mA}$	-	91	-	lm
Viewing Angle ^{*3}	H axis- $2\theta_{1/2}$	$I_F = 175\text{mA}$		145		deg.
	V axis- $2\theta_{1/2}$	$I_F = 175\text{mA}$		145		deg.
CIE x	C_x	$I_F = 175\text{mA}$	-	0.2738	-	-
CIE y	C_y	$I_F = 175\text{mA}$	-	0.2309	-	-
Thermal Resistance (Junction to Solder) ^{*4}	$R_{th(j-s)}$	$I_F = 300\text{mA}$	-	-	5	$^{\circ}\text{C}/\text{W}$
ESD Sensitivity		HBM	2	-	-	Kv
Life Time ^{*5}		$T_j < 125^{\circ}\text{C}$	30,000	-	-	Hrs

Notes :

- (1) Forward voltage measurement allowance is $\pm 0.1\text{V}$
- (2) The luminous Flux value is based on SSC Calibration. Luminous Flux measurement allowance is $\pm 7\%$.
- (3) $2\theta_{1/2}$ is the off-axis where the luminous intensity is 1/2 of the peak intensity.
- (4) R_{th} can be different by T_s at the ambient temperature (PCB : SSC standard)
- (5) Failure means that luminous intensity degrades to 50% of initial value .(L50) The lifetime is estimated by the measured datum at 3khr. (MTTF)

Characteristic Diagram T.B.D

Fig 1. Color Spectrum, $T_a = 25^\circ\text{C}$, $I_F = 300\text{mA}$, RH30%

Fig 2. Radiant pattern, $T_a = 25^\circ\text{C}$


Characteristic Diagram T.B.D

Fig 3. Forward Voltage vs. Forward Current , $T_a = 25^\circ\text{C}$

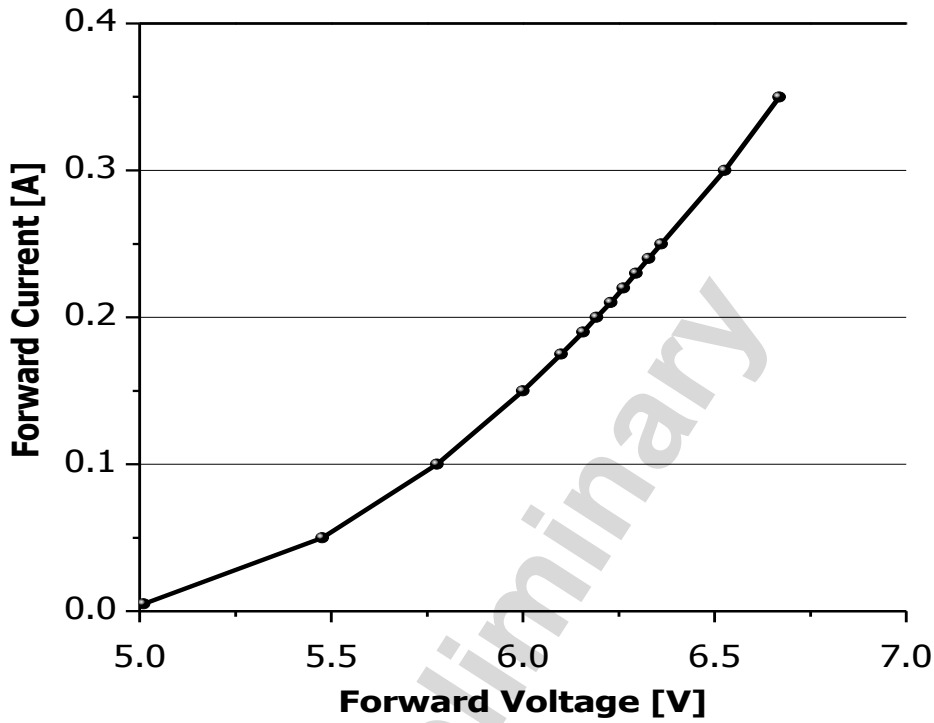
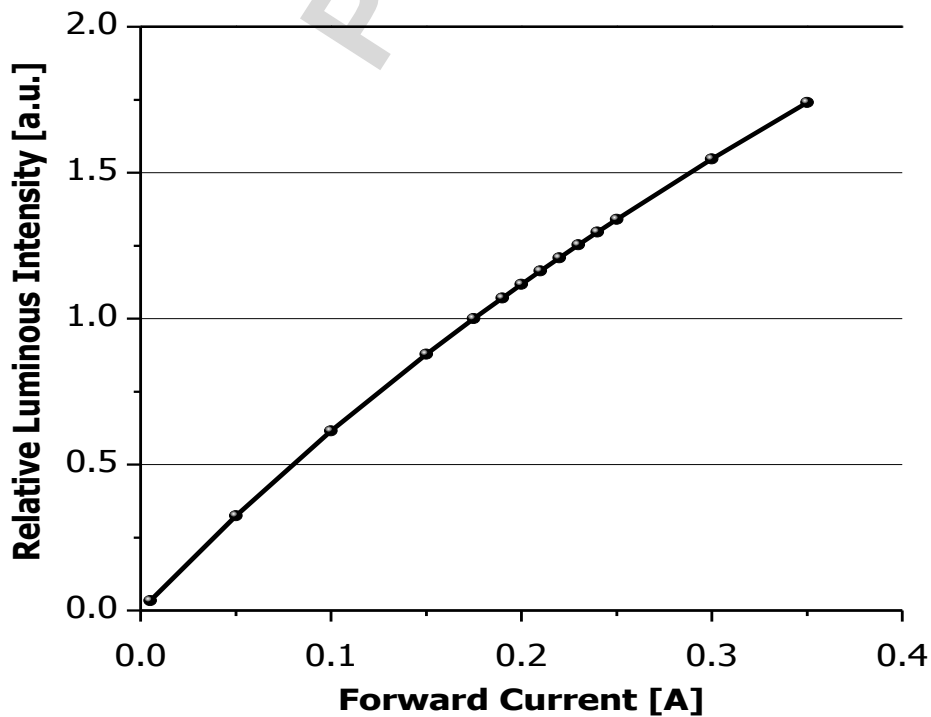


Fig 4. Forward Current vs. Relative Luminous Intensity, $T_a = 25^\circ\text{C}$



Characteristic Diagram

T.B.D

Fig 5. Forward Current vs. CIE X, Y Shift, $T_a = 25^\circ\text{C}$

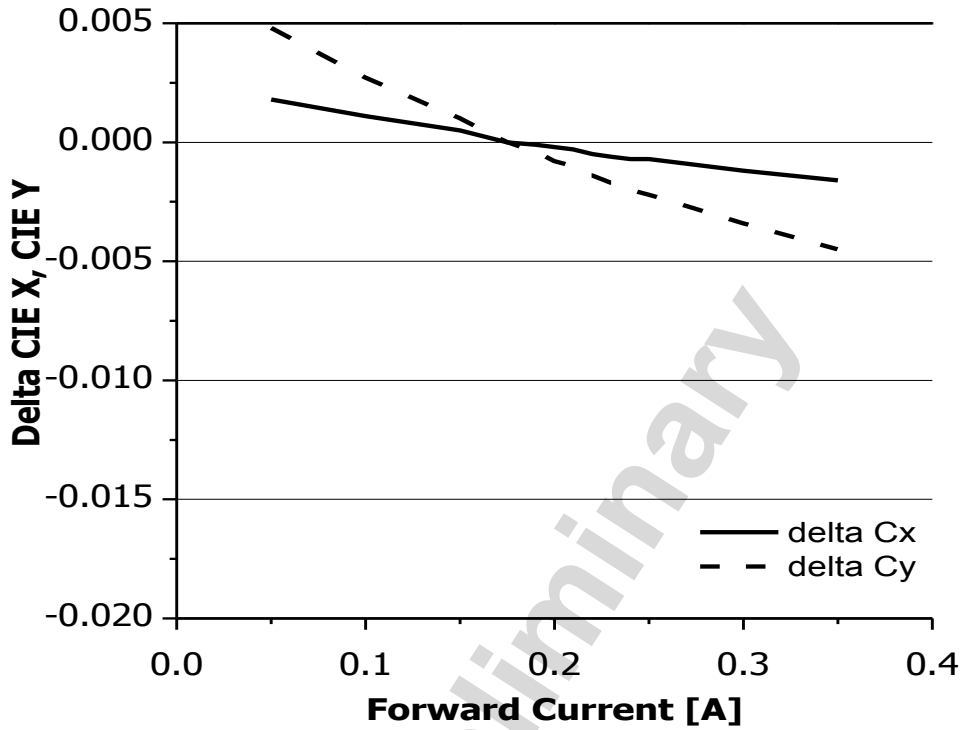
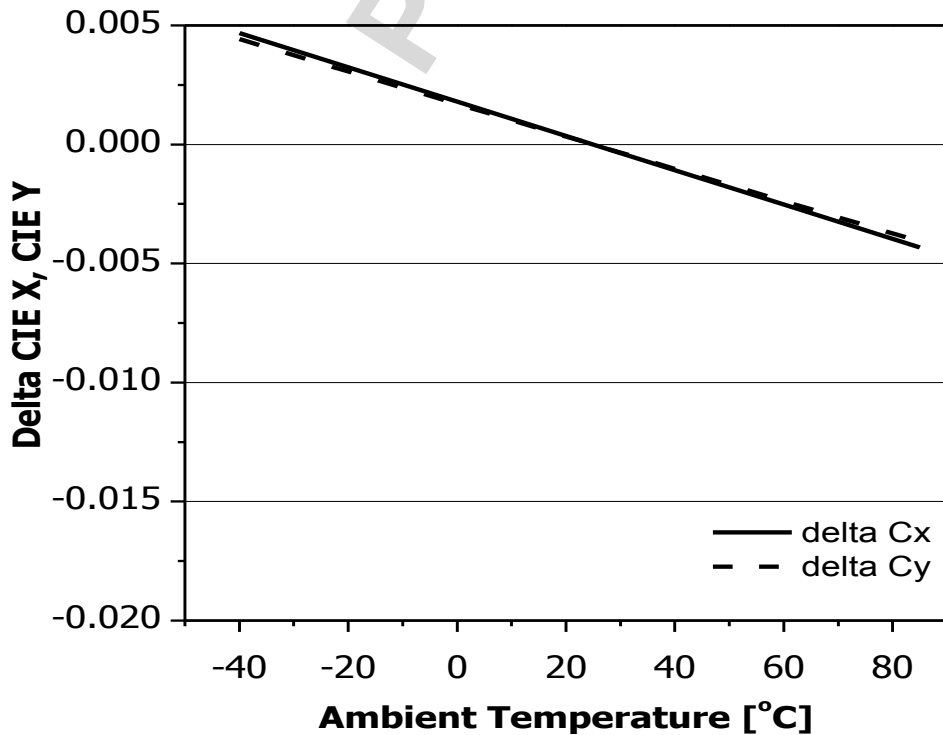
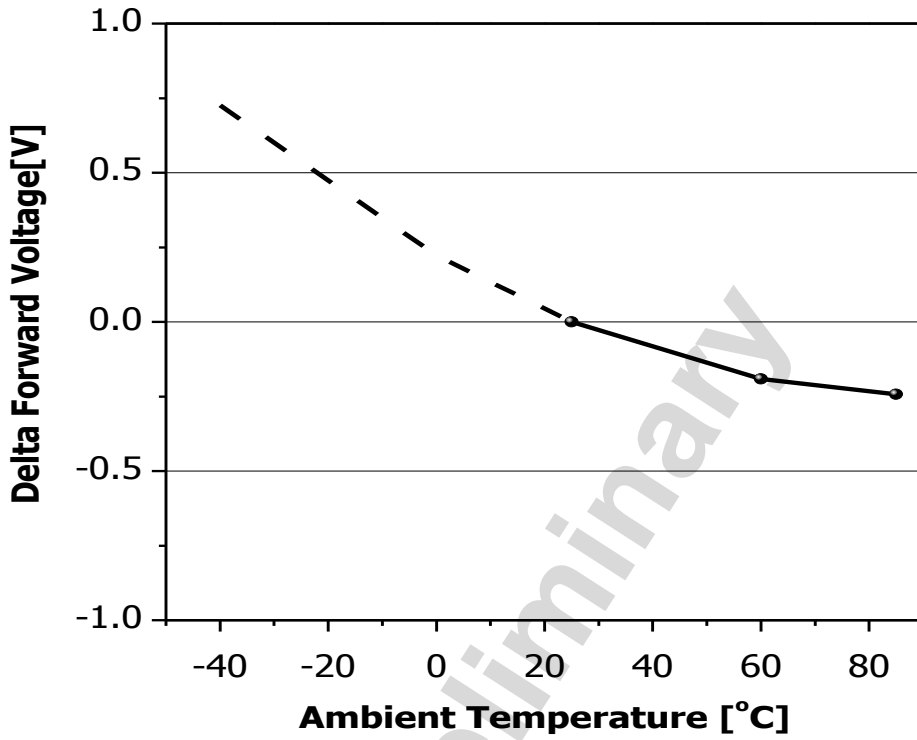
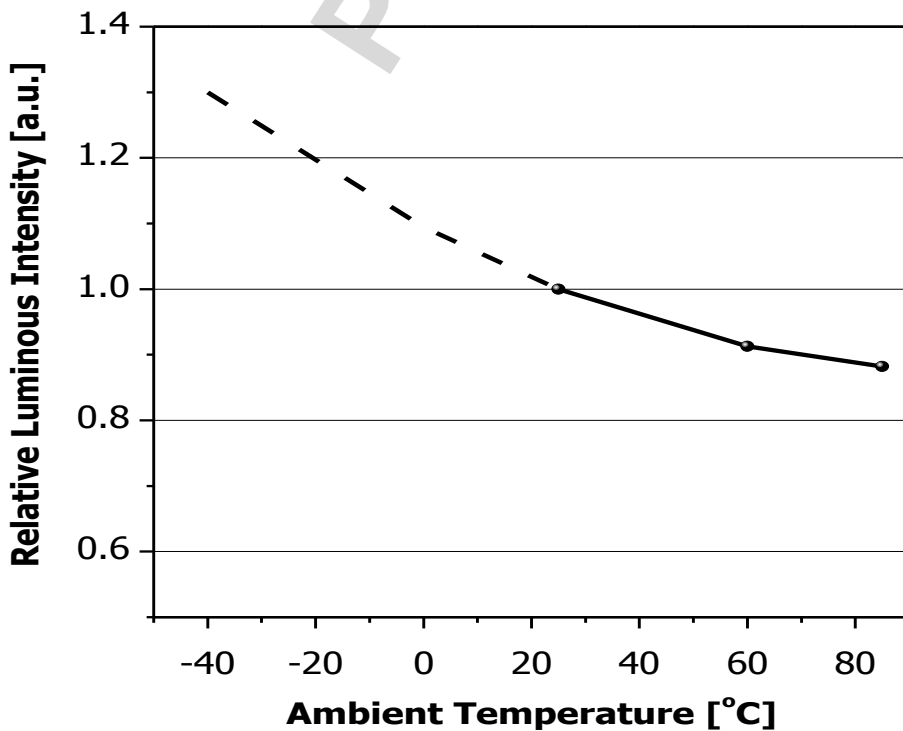


Fig 6. Color Coordinate vs. Ambient Temperature, $I_F = 300\text{mA}$



Characteristic Diagram

T.B.D

Fig 7. Forward Voltage vs. Ambient Temperature, $I_F=300\text{mA}$

Fig 8. Relative Luminous Intensity vs. Ambient Temperature, $I_F=300\text{mA}$


Reliability Test

T.B.D

Table 3. TEST ITEMS AND RESULTS

Item	Reference	Test Condition	Duration / Cycle	Number of Damage
Thermal Shock	Internal Reference	$T_a = -40^{\circ}\text{C}$ (30MIN) \sim 100°C (30MIN)	100 cycle	-
Temperature Cycle	EIAJED-4701	$T_a = -40^{\circ}\text{C}$ (30MIN) \sim 25°C (5MIN) \sim 125°C (30MIN) \sim 25°C (5MIN)	100 cycle	-
Operating Endurance Test	Internal Reference	$T_a = 25^{\circ}\text{C}$, $I_F = 300\text{mA}$	1,000 Hours	-
High Temperature /Humidity Life	Internal Reference	$T_a = 60^{\circ}\text{C}$, RH=90%, $I_F = 300\text{mA}$	1,000 Hours	-
High Temperature Life Test-1	Internal Reference	$T_a = 60^{\circ}\text{C}$, $I_F = 300\text{mA}$	1,000 Hours	-

Table 4. Criteria for Judging the Damage

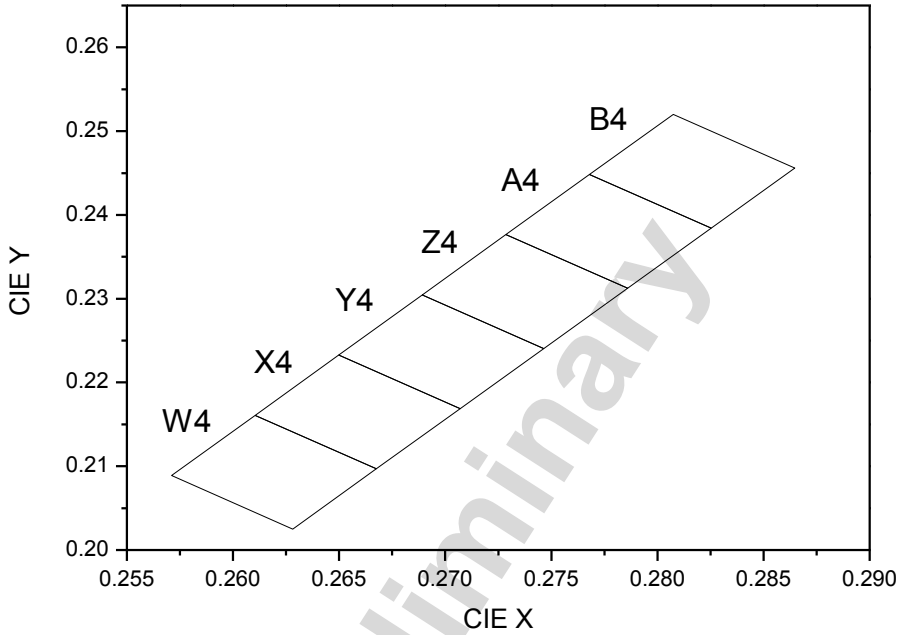
Item	Symbol	Condition	Criteria for Judgment	
			MIN	MAX
Forward Voltage	V_F	$I_F = 300\text{mA}$	-	I.V. ^{*1} \times 1.2
Luminous Flux	Φ_V	$I_F = 300\text{mA}$	I.V. ^{*1} \times 0.7	-

Notes :

⁽¹⁾ I.V. : Initial Value

Color Bin Structure

T.B.D

CIE Chromaticity Diagram


RANK	x1	y1	x2	y2
	x3	y3	x4	y4
W4	0.2571	0.2089	0.2610	0.2161
	0.2668	0.2097	0.2628	0.2025
X4	0.2610	0.2161	0.2650	0.2233
	0.2707	0.2169	0.2668	0.2097
Y4	0.2650	0.2233	0.2689	0.2305
	0.2747	0.2241	0.2707	0.2169
Z4	0.2689	0.2305	0.2729	0.2376
	0.2786	0.2312	0.2747	0.2241
A4	0.2729	0.2376	0.2768	0.2448
	0.2825	0.2384	0.2786	0.2312
B4	0.2768	0.2448	0.2807	0.2520
	0.2865	0.2456	0.2825	0.2384

* Measurement Uncertainty of the Color Coordinates is ± 0.007

Color Bin Structure

T.B.D

Table 5. Bin Code description
Part Number : SWWVA2S0E

Bin Code			
Luminous Flux	CIE	Peak Wave Length	Forward Voltage
A090	Z4	B	Z60

Luminous Flux [lm] @ I _F = 175mA			Color Rank @ I _F = 175mA	Peak Wave Length [nm] @ I _F = 175mA			Forward Voltage [V] @ I _F = 175mA		
Bin Code	Min.	Max.	W4~B4	Bin Code	Min.	Max.	Bin Code	Min.	Max.
A078	78.0	81.0	Available Ranks	A	436	441	Z58	5.8	6.0
A081	81.0	84.0		B	441	447	Z60	6.0	6.2
A084	84.0	87.0		C	447	452	Z62	6.2	6.4
A087	87.0	90.0					Z64	6.4	6.6
A090	90.0	93.0							
A093	93.0	96.0							
A096	96.0	99.0							
A099	99.0	102.0							
A102	102.0	105.0							

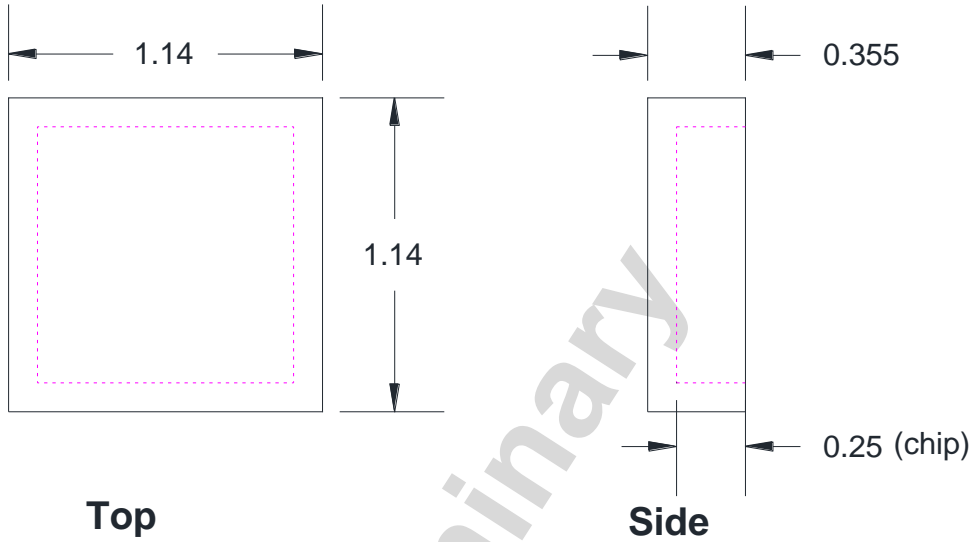
Available Ranks

Mechanical Dimensions

T.B.D

(Tolerance: ± 0.1 , Unit: mm)

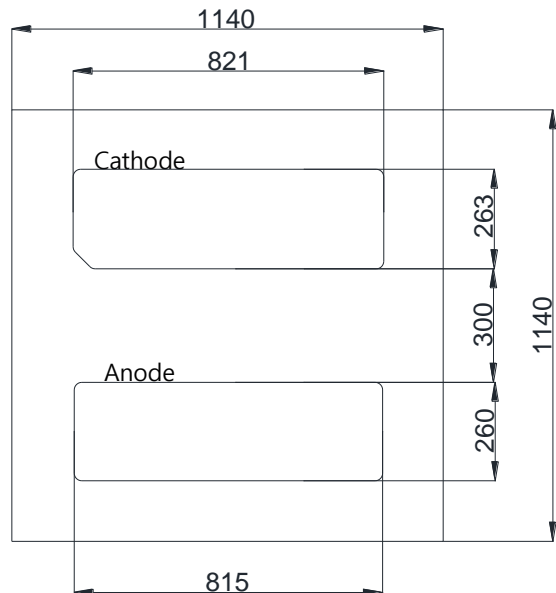
PKG Outline dimension



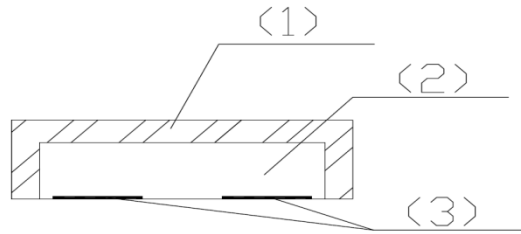
< Inner circuit >

< Recommended Solder Pattern >

(Unit: μm)




Material Structure





No.	LIST	MATERIAL
①	Encapsulation	Silicone, Phosphor
②	Chip Source	GaN ON SAPPHIRE
③	Solder-PAD	Metal (Au)


Preliminary

Product Nomenclature
T.B.D

RANK :


QUANTITY : #####


LOT NUMBER : ##### #### ##


SSC PART NUMBER : ### ## ## ##





Table 6. Part Numbering System : X₁X₂X₃ X₄X₅ X₆X₇X₈X₉

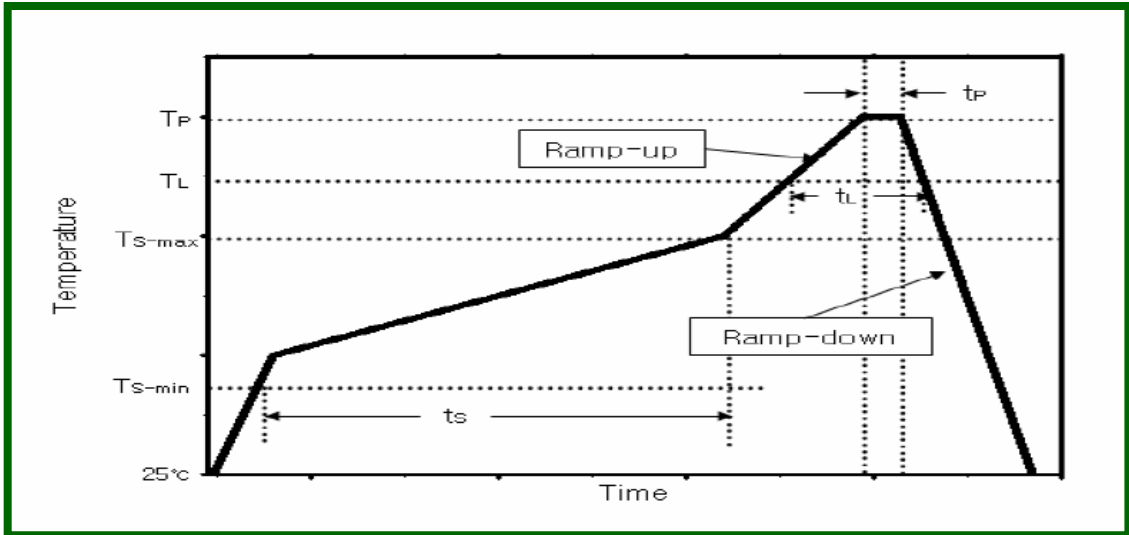
Part Number Code	Description	Part Number	Value
X ₁	Company	S	
X ₂	LED series number	W	WICOP
X ₃ X ₄	Color Specification	WV	
X ₅ X ₆ X ₇	PKG series	A2S	WICOP1140 2Cell MJT
X ₈	Revision number	0	
X ₉	Chip Company	E	SVC

Table 7. Part Numbering System :
Y1Y2Y3Y4Y5 – Y6Y7Y8Y9Y10 – Y11Y12Y13 – Y14Y15Y16- Y17Y18Y19Y20Y21Y22

Lot Number Code	Description	Lot Number	Value
Y ₁ Y ₂	Year	16	
Y ₃	Month	9	
Y ₄ Y ₅	Day	09	
Y ₆	Company	S	
Y ₇ Y ₈ Y ₉ Y ₁₀	SSC's Number	0017	0001-9999 allowance
Y ₁₁ Y ₁₂ Y ₁₃ -Y ₁₄ Y ₁₅ Y ₁₆	Order of Tapping	014-001	
Y ₁₇ Y ₁₈ Y ₁₉ Y ₂₀ Y ₂₁ Y ₂₂ Y ₂₃	SSC's Number	7370052	Automatic

Reflow Soldering Characteristics

(1) Reflow solder conditions / profile

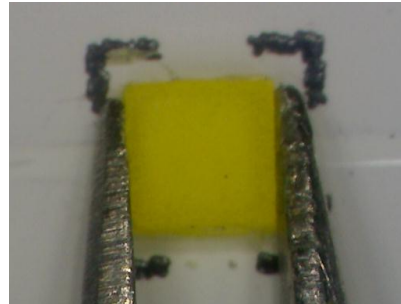


Reflow condition	Pb-Free assembly
Average ramp-up rate (T_{S-max} to Peak)	2~3°C / second
Preheat Temperature Min (T_{S-min})	150°C
Preheat Temperature Max (T_{S-max})	200°C
Time maintained above: : Liquidus Temperature (T_L)	217~220°C
Time maintained above: Time (t_L)	60~150 seconds
Peak Temperature (T_P)	250°C
Time within 5°C of actual Peak Temperature (t_p)	20~40 seconds
ramp-down rate	4~6°C / second
Time 25°C to Peak Temperature	6 minutes max

Note : In case that the soldered products are reused in soldering process, we don't guarantee the products.

Handling of Silicone Resin for LEDs

- (1) During processing, mechanical stress on the surface should be minimized as much as possible.
- (2) Sharp objects of all types should not be used to pierce the sealing compound.



- (3) When it is mounted WICOP on the PCB, material of the pick and place nozzle must be used soft form in SMT.
- (4) It must be choosing a pick and place nozzle which is smaller than the WICOP's size.
- (5) (2),(3) contents is necessary in SMT to prevent surface of WICOP
- (6) In case WICOP is not recommended isopropyl alcohol and ultrasonic, solvent for cleaning. Isopropyl alcohol and ultrasonic, solvent cleaning may cause damage to the WICOP
- (7) If you want to be cleaning particle on surface of WICOP, Seoul semiconductors suggests using cotton bud for cleaning after soldering of components
- (8) Avoid leaving fingerprints on silicone resin parts.

Precaution for Use

(1) Storage conditions

Keep the product in a dry box or a desiccator with a desiccant in order to prevent moisture absorption.

a. Keep it at a temperature in the range from 5°C to 30°C and at a humidity of less than 50% RH. The product should be kept within a year.

(2) After opening the package .

When soldering, this could result in a decrease of the photoelectric effect or light intensity.

a. Soldering should be done right after mounting the product.
 b. Keep the temperature in the range from 5°C to 30°C and the humidity at less than 60%.

Soldering should be done within 7 days after opening the desiccant package.

If the product has been exposed for more than 7 days after opening the package or the indicating color of the desiccator changes, the product must be baked at a temperature between $65 \pm 5^\circ\text{C}$ for less than 24 hours.

An unused and unsealed product should be repacked in a desiccant package and kept sealed in a dry atmosphere.

Stored at a humidity of less than 10% RH.

(3) Precautions for use

Any external mechanical force or excessive vibration should not be applied to the product during cooling after soldering, and it is preferable to avoid rapid cooling.

The product should not be mounted on a distorted part of PCB.

Gloves or wrist bands for ESD(Electric Static Discharge) should be wore in order to prevent ESD and surge damage, and all devices and equipments must be grounded to the earth.

Turn on test is conducted only at room temperature. Also, Should not be turned on at high temperatures.

(4) Miscellaneous

Radiation resistance is not considered.

When cleaning the product, any kind of fluid such as water, oil and organic solvent must not be used and IPA(Isopropyl Alcohol) must be used.

When using the product, operating current should be settled in consideration of the maximum ambient temperature.

Its appearance or specification for improvement is subject to change without notice.

Precaution for Use

- (5) LEDs are sensitive to Electro-Static Discharge (ESD) and Electrical Over Stress (EOS).
Below is a list of suggestions that Seoul Semiconductor purposes to minimize these effects.

a. ESD (Electro Static Discharge)

Electrostatic discharge (ESD) is defined as the release of static electricity when two objects come into contact. While most ESD events are considered harmless, it can be an expensive problem in many industrial environments during production and storage. The damage from ESD to LEDs may cause the product to demonstrate unusual characteristics such as:

- Increase in reverse leakage current lowered turn-on voltage
- Abnormal emissions from the LED at low current

The following recommendations are suggested to help minimize the potential for an ESD event.
One or more recommended work area suggestions:

- Ionizing fan setup
- ESD table/shelf mat made of conductive materials
- ESD safe storage containers

One or more personnel suggestion options:

- Antistatic wrist-strap
- Antistatic material shoes
- Antistatic clothes

Environmental controls:

- Humidity control (ESD gets worse in a dry environment)

Precaution for Use

b. EOS (Electrical Over Stress)

Electrical Over-Stress (EOS) is defined as damage that may occur when an electronic device is subjected to a current or voltage that is beyond the maximum specification limits of the device.

The effects from an EOS event can be noticed through product performance like:

- Changes to the performance of the LED package
(If the damage is around the bond pad area and since the package is completely encapsulated the package may turn on but flicker show severe performance degradation.)
- Changes to the light output of the luminaire from component failure
- Components on the board not operating at determined drive power

Failure of performance from entire fixture due to changes in circuit voltage and current across total circuit causing trickle down failures. It is impossible to predict the failure mode of every LED exposed to electrical overstress as the failure modes have been investigated to vary, but there are some common signs that will indicate an EOS event has occurred:

- Damaged may be noticed to the bond wires (appearing similar to a blown fuse)
- Damage to the bond pads located on the emission surface of the LED package
(shadowing can be noticed around the bond pads while viewing through a microscope)
- Anomalies noticed in the encapsulation and phosphor around the bond wires.
- This damage usually appears due to the thermal stress produced during the EOS event.

c. To help minimize the damage from an EOS event Seoul Semiconductor recommends utilizing:

- A surge protection circuit
- An appropriately rated over voltage protection device
- A current limiting device

Company Information

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Company Information

Seoul Semiconductor (www.SeoulSemicon.com) manufactures and packages a wide selection of light emitting diodes (LEDs) for the automotive, general illumination/lighting, Home appliance, signage and back lighting markets. The company is the world's fifth largest LED supplier, holding more than 10,000 patents globally, while offering a wide range of LED technology and production capacity in areas such as "nPola", "Acrich", the world's first commercially produced AC LED, and "Acrich MJT - Multi-Junction Technology" a proprietary family of high-voltage LEDs.

The company's broad product portfolio includes a wide array of package and device choices such as Acrich and Acirch2, high-brightness LEDs, mid-power LEDs, side-view LEDs, and through-hole type LEDs as well as custom modules, displays, and sensors.

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